

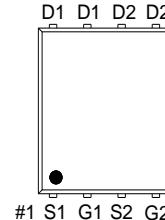
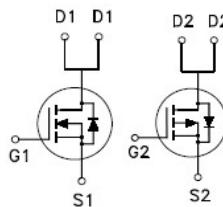
**NIKO-SEM****N- & P-Channel Enhancement Mode Field Effect Transistor****PA110NK**

PDFN 5x6P

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

	$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
Q2	-100V	180mΩ	-10A
Q1	100V	110mΩ	9A



G. GATE  
D. DRAIN  
S. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	Q2	Q1	UNITS
Drain-Source Voltage		$V_{DS}$	-100	100	V
Gate-Source Voltage		$V_{GS}$	$\pm 25$	$\pm 20$	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	-10	9	A
	$T_C = 100^\circ\text{C}$		-6.5	5.7	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	-40	25	
Continuous Drain Current <sup>3</sup>	$T_A = 25^\circ\text{C}$	$I_D$	-2.7	3	W
	$T_A = 70^\circ\text{C}$		-2.2	2.5	
Avalanche Current		$I_{AS}$	-11	6	
Avalanche Energy	$L = 1\text{mH}$	$E_{AS}$	61	18	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	42	21	W
	$T_C = 100^\circ\text{C}$		17	8	
Power Dissipation <sup>3</sup>	$T_A = 25^\circ\text{C}$	$P_D$	3	2.5	W
	$T_A = 70^\circ\text{C}$		1.9	1.6	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS	
Junction-to-Ambient <sup>2</sup>	$t \leq 10\text{s}$	$R_{\theta JA}$	Q2	42	°C / W	
			Q1	50		
Junction-to-Ambient <sup>2</sup>	Steady-State	$R_{\theta JA}$	Q2	63		
			Q1	73		
Junction-to-Case		$R_{\theta JC}$	Q2	3		
			Q1	6		

<sup>1</sup>Pulse width limited by maximum junction temperature  $T_{J(MAX)}=150^\circ\text{C}$ .

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

<sup>3</sup>The Power dissipation is based on  $R_{\theta JA}$   $t \leq 10\text{s}$  value.

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**ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT	
			MIN	TYP	MAX		
<b>STATIC</b>							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	Q2	-100		V	
		V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	Q1	100			
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	Q2	-1.3	-1.8	-2.3	
		V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	Q1	1	1.8	3	
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±25V	Q2			±100	
		V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	Q1			±100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -80V, V <sub>GS</sub> = 0V	Q2			-1	
		V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V	Q1			1	
		V <sub>DS</sub> = -80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 55 °C	Q2			-10	
		V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 55 °C	Q1			10	
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	Q2		173	190	
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 6A	Q1		86	120	
		V <sub>GS</sub> = -10V, I <sub>D</sub> = -5A	Q2		159	180	
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 6A	Q1		80	110	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = -5V, I <sub>D</sub> = -5A	Q2		19		
		V <sub>DS</sub> = 5V, I <sub>D</sub> = 6A	Q1		30		
<b>DYNAMIC</b>							
Input Capacitance	C <sub>iss</sub>	Q2 V <sub>GS</sub> = 0V, V <sub>DS</sub> = -25V f = 1MHz Q1 V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V f = 1MHz	Q2	1232	1540	1840	pF
Output Capacitance	C <sub>oss</sub>		Q1	492	616	739	
Reverse Transfer Capacitance	C <sub>rss</sub>		Q2	90	113	135	
Gate Resistance	R <sub>g</sub>		Q1	44	55	66	
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>		Q2	46	77	108	
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>		Q1	18	31	43	
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>	Q2 V <sub>DS</sub> = -50V V <sub>GS</sub> = -10V, I <sub>D</sub> = -5A Q1 V <sub>DS</sub> = 50V V <sub>GS</sub> = 10V, I <sub>D</sub> = 6A	Q2	1.9	3.8	5.7	Ω
			Q1	0.8	1.5	2.3	
			Q2	23	29	34.8	
			Q1	11	14	16.8	
			Q2	12	15	18	
			Q1	6.4	8	9.6	
			Q2	3.3	4.1	4.9	
			Q1	1.4	1.8	2.2	
			Q2	4.3	7.1	9.9	nC
			Q1	2.6	4.3	6	

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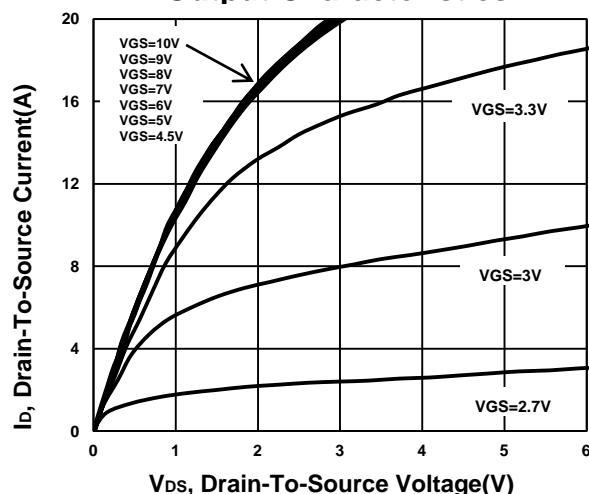
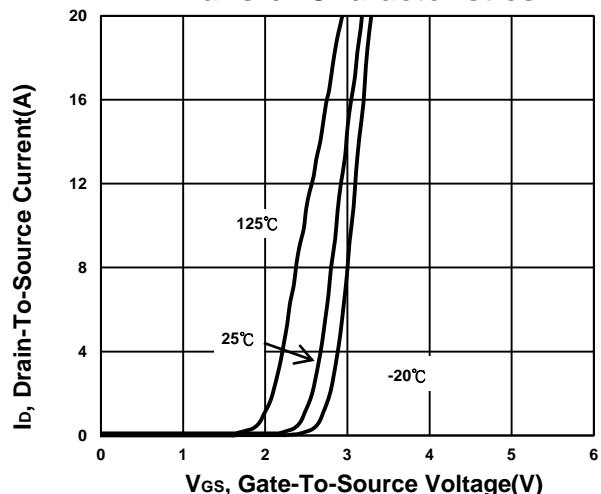
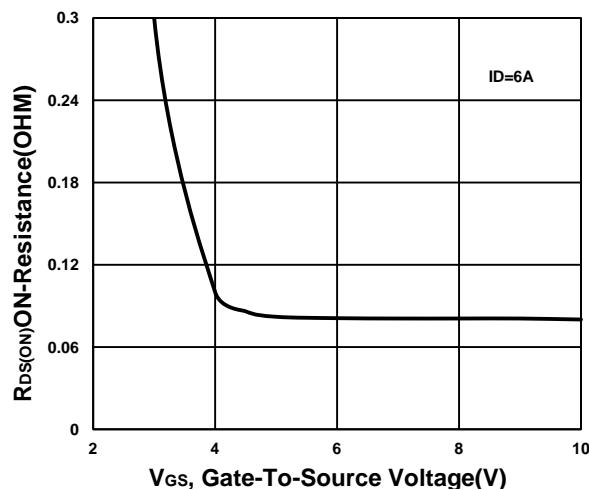
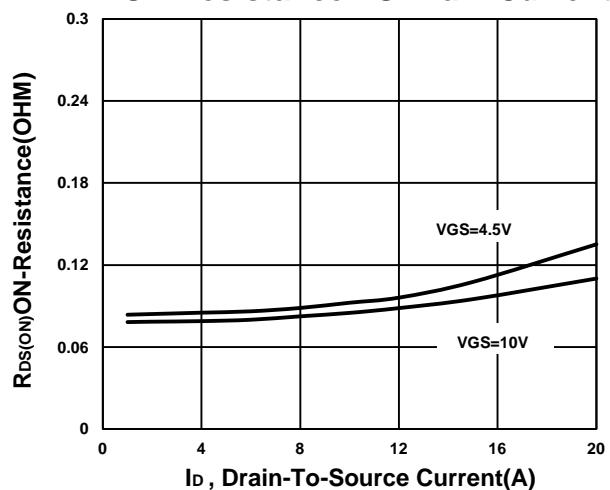
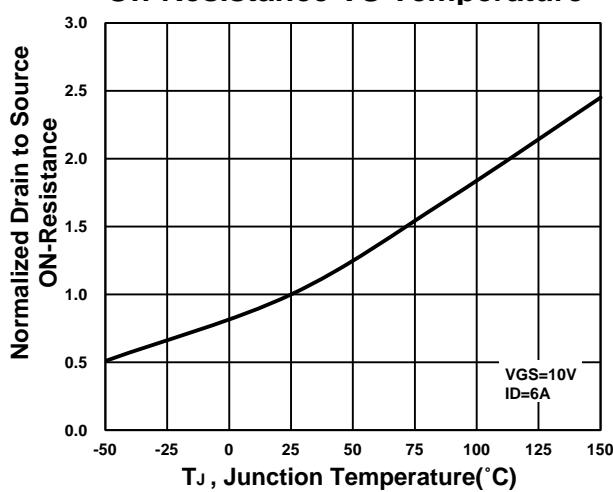
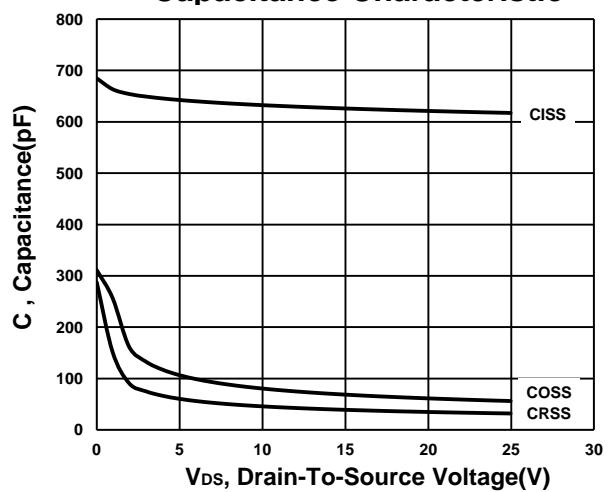
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	Q2 , $V_{DS} = -50V$ $I_D \approx -5A$ $V_{GS} = -10V$ , $R_{GEN} = 6\Omega$	Q2	17		nS
Rise Time <sup>2</sup>	$t_r$		Q1	11		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		Q2	20		
Fall Time <sup>2</sup>	$t_f$		Q1	21		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current	$I_S$	Q2 Q1			-10	A
Forward Voltage <sup>1</sup>	$V_{SD}$				9	
Reverse Recovery Time	$t_{rr}$	$I_F = -5A$ $V_{GS} = 0V$	Q2		-1.2	V
		$I_F = 6A$ , $V_{GS} = 0V$	Q1		1.4	
Reverse Recovery Charge	$Q_{rr}$	Q2 $I_F = -5A$ $dI_F/dt = 100A/\mu S$	Q2	21	43	nS
		Q1 $I_F = 6A$ , $dI_F/dt = 100A/\mu S$	Q1	11	23	
		Q2 $I_F = -5A$ $dI_F/dt = 100A/\mu S$	Q2	43	87	nC
		Q1 $I_F = 6A$ , $dI_F/dt = 100A/\mu S$	Q1	12	25	

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

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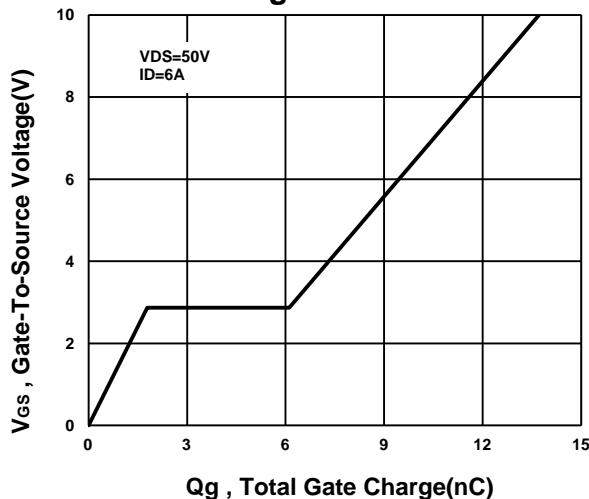
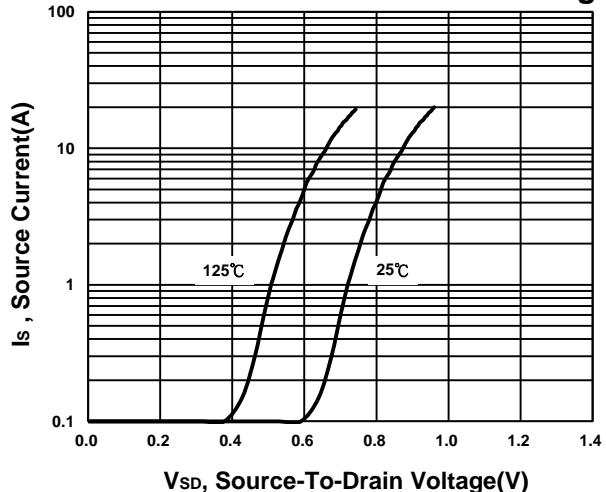
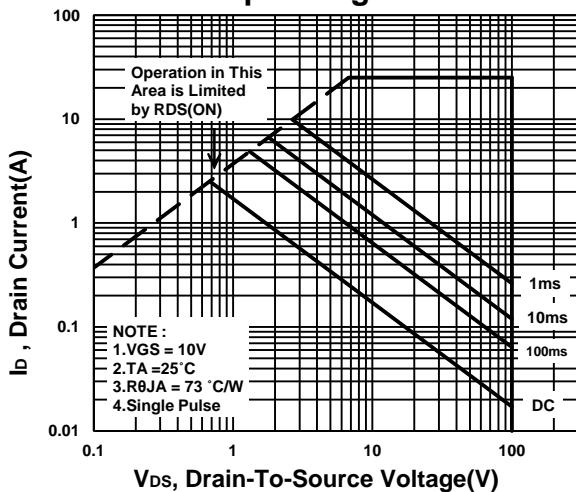
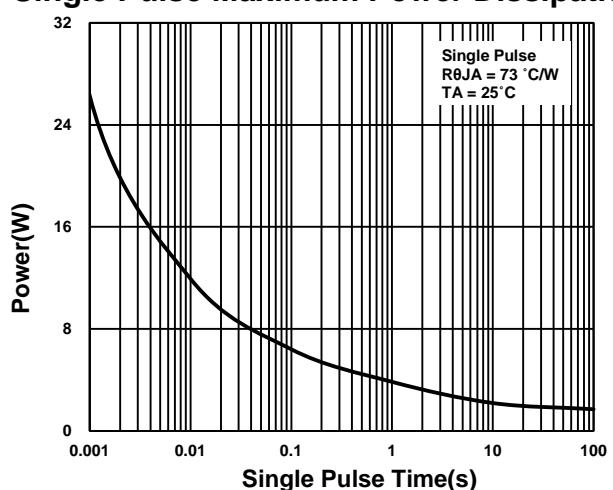
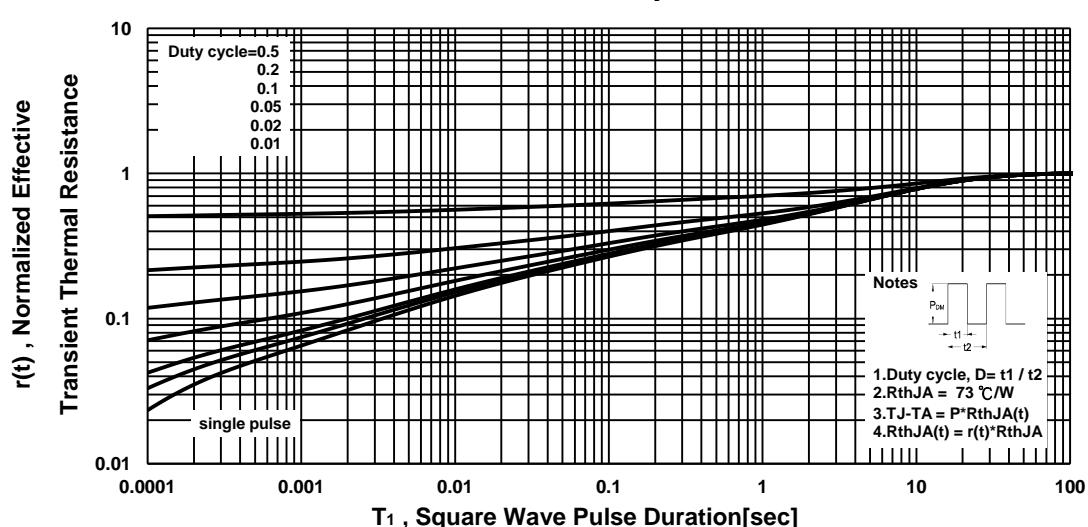
Halogen-Free &amp; Lead-Free

**TYPICAL PERFORMANCE CHARACTERISTICS****N-CHANNEL****Output Characteristics****Transfer Characteristics****On-Resistance VS Gate-To-Source Voltage****On-Resistance VS Drain Current****On-Resistance VS Temperature****Capacitance Characteristic**

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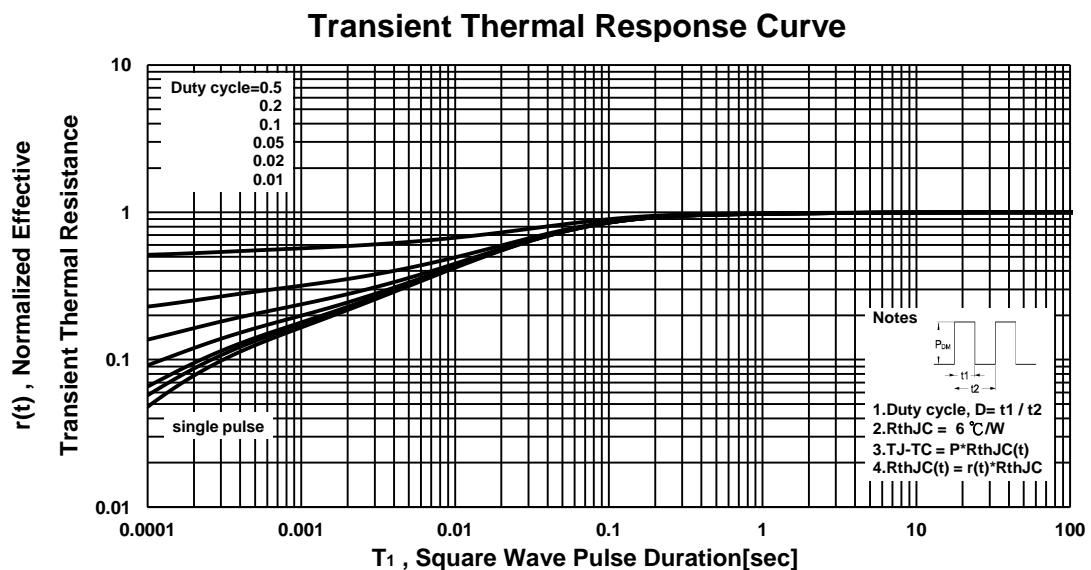
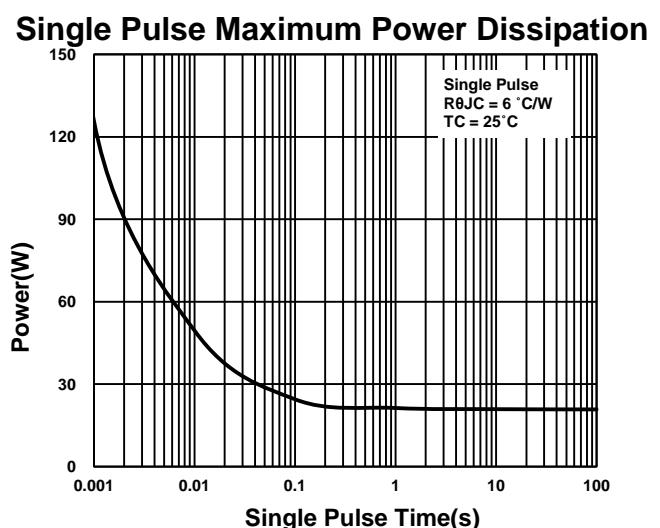
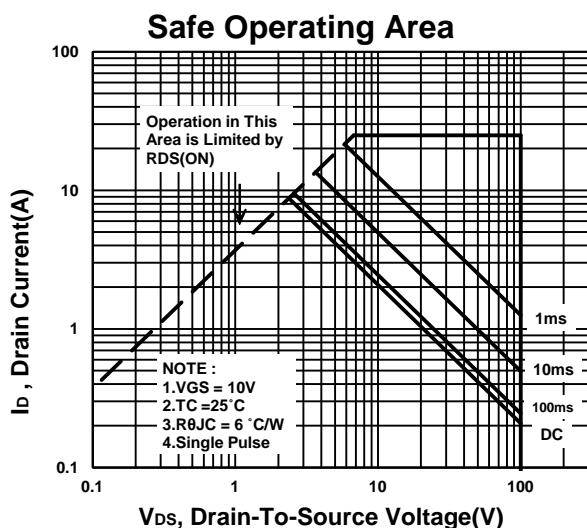
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**Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**

**NIKO-SEM**

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Effect Transistor**

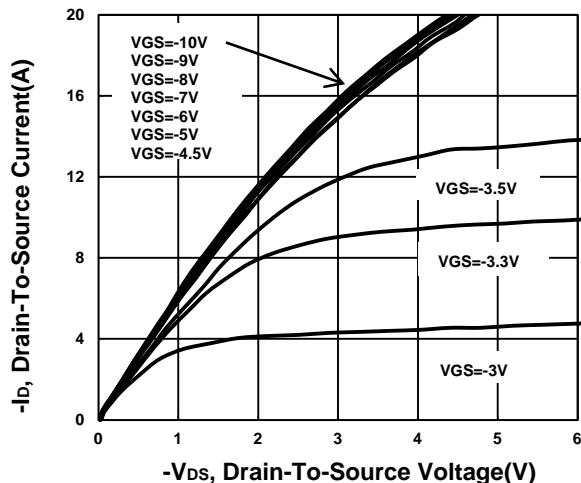
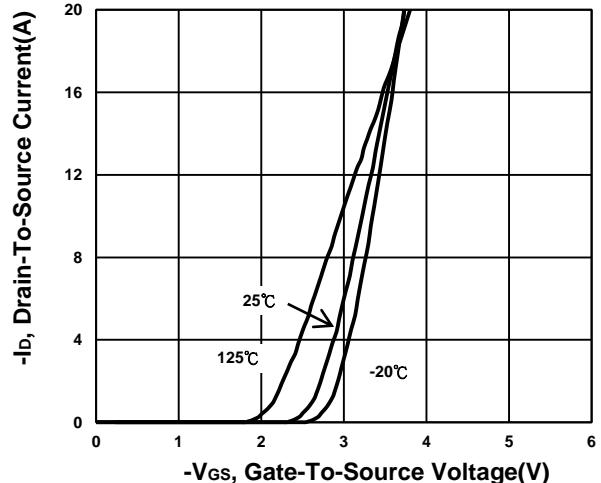
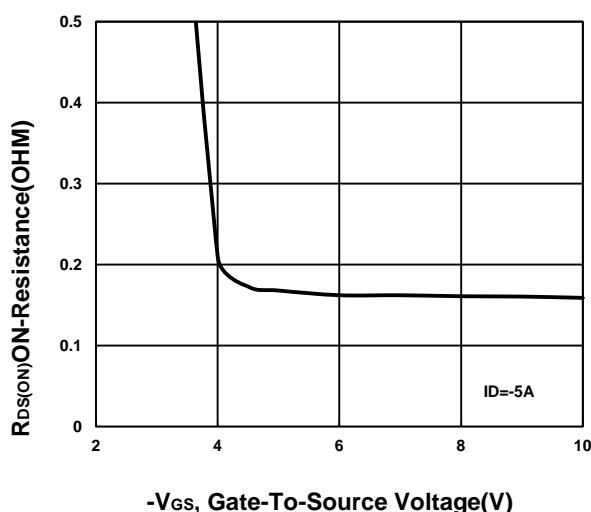
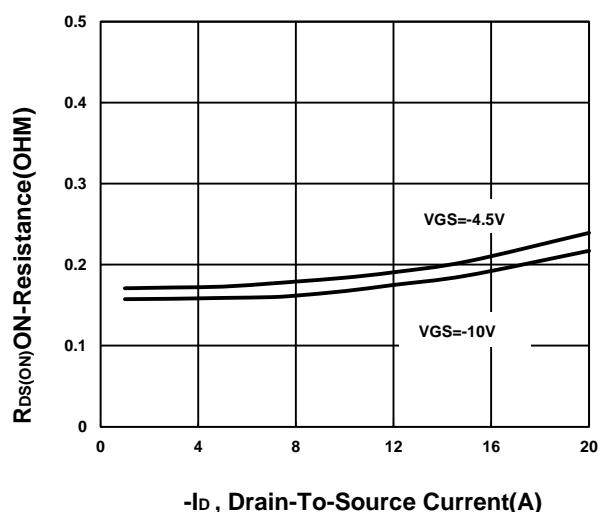
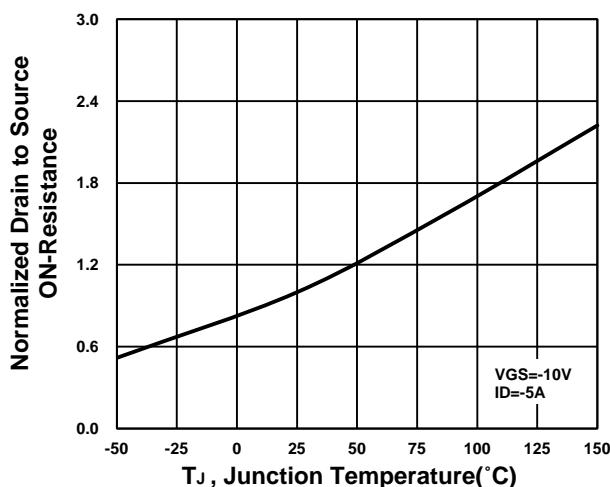
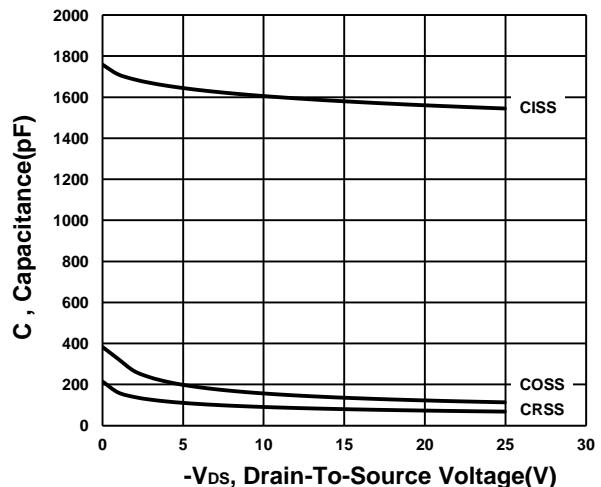
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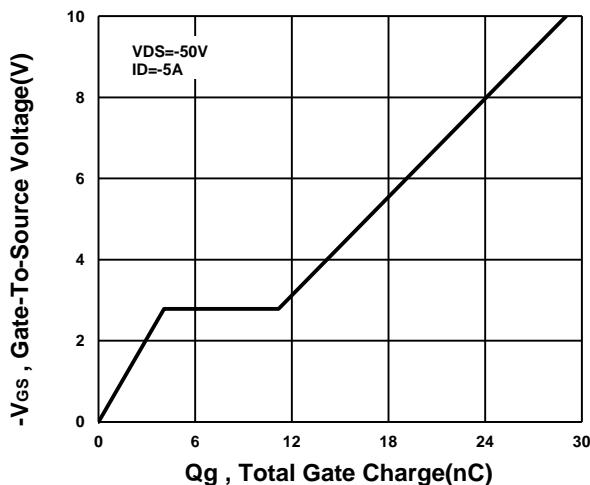
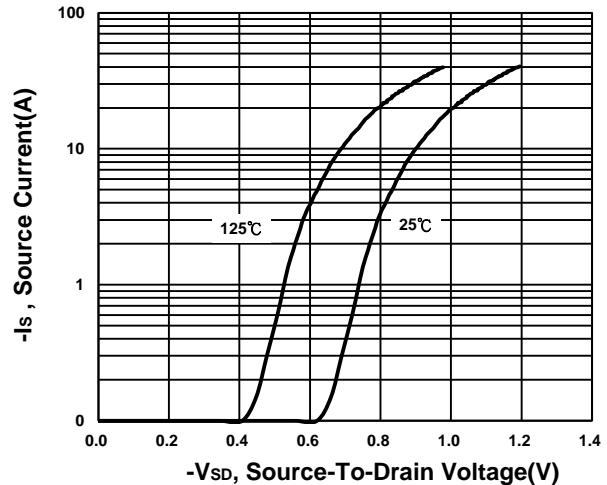
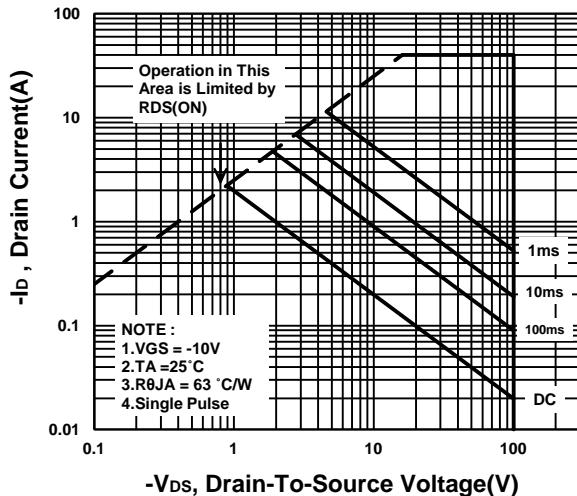
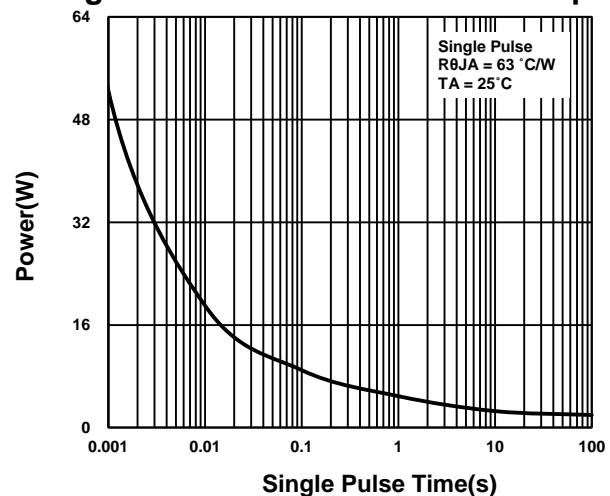
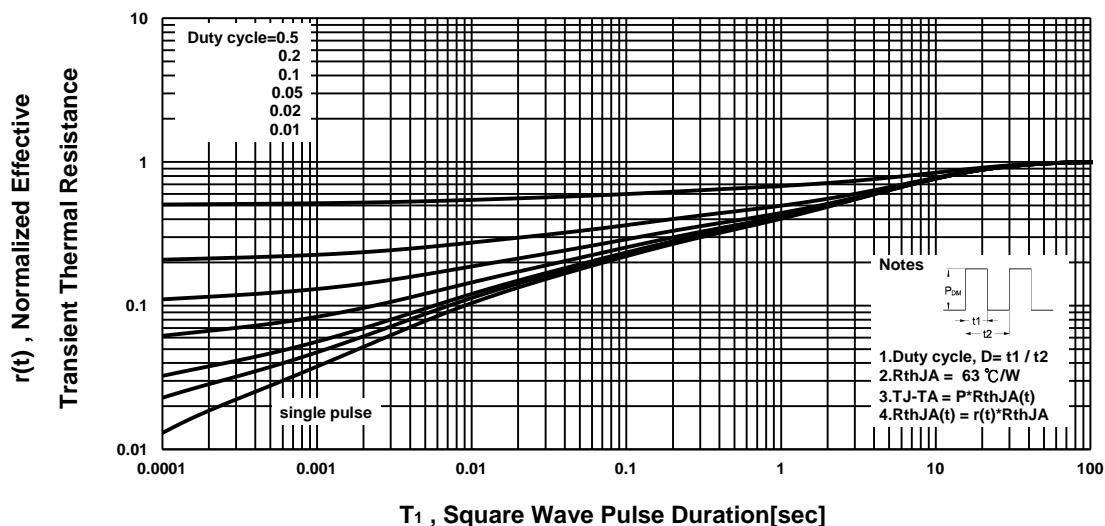
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**P-CHANNEL****Output Characteristics****Transfer Characteristics****On-Resistance VS Gate-To-Source Voltage****On-Resistance VS Drain Current****On-Resistance VS Temperature****Capacitance Characteristic**

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**Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**

**NIKO-SEM**

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